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NOV 09 2007

### AMENDMENTS TO THE CLAIMS

The following listing of claims will replace all prior versions, and listings, of claims in the application:

#### Listing of Claims:

Claims 1 through 39 (Cancelled)

40. (Currently Amended): A method for evaluating a design for a transformer comprising:

- (a.) providing a database comprising:
  - results of a test performed on each of a plurality of transformers;
  - criteria sets for evaluating the results of the tests, each criteria set being applicable to a particular transformer design; and
  - identification information associated with the criteria sets and the results of the tests, the identification data including transformer design identification;
- (b.) retrieving the test results for a certain transformer design from the database using the identification information;
- (c.) retrieving the criteria for the certain transformer design from the database using the identification information;
- (d.) comparing the retrieved test results to the retrieved criteria;
- (e.) counting the number of the retrieved test results that do not satisfy the retrieved criteria;
- (f.) generating an indication that the certain transformer design needs further analysis only if at least a predetermined quantity of the retrieved test results do not satisfy the retrieved criteria; and
- (g.) displaying the indication on a display device;
- (h) determining that the certain transformer design over-performs if the retrieved test results consistently exceed the retrieved criteria; and
- (i) modifying the certain design to reduce the cost of components required by the transformer design.

41. (Previously Presented): The method of claim 40, wherein the predetermined quantity of the test results is a predetermined numerical total.

42. (Previously Presented): The method of claim 40, wherein the predetermined quantity of the test results is a predetermined percentage of the test results.

43. (Previously Presented): The method of claim 40, wherein the test is selected from the group consisting of no-load loss, impedance, transformation ratio, turn to turn faults, high potential, double induced, impulse, and heat run.

44. (Cancelled)